

Page 1 of 58 Report No.: 18230EC20193501

Report **EMC** Test

Shenzhen JHC Technology Development Co., Client Name

LTD

B Area, 3rd floor, A Block Junxiangda

Building, No.9 Zhongshanyuan Road, **Client Address**

Nanshan Distr., Shenzhen, China

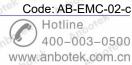
Industrial Embedded Computer Product Name

Oct. 11, 2022 Report Date

Shenzhen Anbotek Compliance Laboratory Limited











Report No.: 18230EC20193501

Page 2 of 58

Contents

| 1. General Information | 5 |
|---|-------|
| 1.1. Client Information | 5 |
| 1.2. Description of Device (EUT) | 5 |
| 1.3. Auxiliary Equipment Used During Test 1.4. Description of Test Mode | 6 |
| 1.4. Description of Test Mode | 7 |
| 1.5. Test Summary | 7 N |
| 1.5. Test Summary | 8 |
| 1.7 Description of Test Facility | An 11 |
| 1.8. EMS Performance Criteria 2. Power Line Conducted Emission Test | 12 |
| 2. Power Line Conducted Emission Test | 13 |
| 2.1. Test Standard and Limit | 13 |
| 2.1. Test Standard and Limit 2.2. Test Setup | 13 |
| 2.3. Test Procedure | 14 |
| 2.4. Test Results | 14 |
| Asymmetric Mode Conducted Emission at Telecom Port | 17 |
| 3.1. Test Standard and Limit | 17 |
| | |
| 3.3. Test Procedure | 18 |
| 3.4. Test Results | 18 |
| 3.4. Test Results 4. Radiated Emission Test (Below 1 GHz) | 20 |
| 4.1. Test Standard and Limit | 20 |
| 4.2. Test Setup | 20 |
| 4.3. Test Procedure | 21 |
| 4.4. Test Results 5. Radiated Emission Test (Above 1GHz) | 21 |
| 5. Radiated Emission Test (Above 1GHz) | 24 |
| 5.1 Test Standard and Limit | 24 n |
| | |
| 5.3. Test Procedure | 25 |
| 5.4. Test Results | 25 |
| 6. Harmonic Current Test | 28 |
| 6.1. Test Standard | 28 |
| 6.2. Test Setup | 28 |
| 6.1. Test Standard | 28 |
| 6.4. Test Results | 28 |
| 6.4. Test Results | 29 |
| 7.1. Test Standard | 29 |
| 7.2. Test Setup | 29 |
| 7. Voltage Fluctuations & Flicker Test 7.1. Test Standard 7.2. Test Setup 7.3. Test Procedure 7.4. Test Results | 29 |
| 7.4. Test Results | 29 |

Shenzhen Anbotek Compliance Laboratory Limited





| Report No.: 18230EC20193501 | Page 3 of 58 |
|---|------------------------|
| 8. Electrostatic Discharge Immunity Test | ypo, Tryough Whole |
| Report No.: 18230EC20193501 8. Electrostatic Discharge Immunity Test 8.1. Test Specification 8.2. Test Setup 8.3. Test Procedure 8.4. Test Results | Kubote Anu tek motek |
| 8.2. Test Setup | |
| 8.3. Test Procedure | And And |
| 8.4. Test Results | |
| 9. RF Field Strength Immunity Test | lek Yupo, " by makek |
| 9.1 Test Specification | |
| 9.2. Test Setup | |
| 9.3. Test Procedure | Anbo. A harmonia |
| 9.4. Test Results | anbote. Ann |
| 9.4. Test Results | Aupo, W |
| 10.1 Test Specification | |
| 10.2 Test Setup | |
| 40.2 Test Deservices | |
| 10.4. Test Results | August Village Village |
| 10.3. Test Procedure 10.4. Test Results 11. Surge Immunity Test 11.1. Test Specification 11.2. Test Setup 11.3. Test Procedure | Ann Anbo |
| 11.1. Test Specification | Anbore Anbore |
| 11.2. Test Setup | Ambores Amb |
| 11.3. Test Procedure | k hotek Anbo, k |
| 11.4. Test Results | w. otek Vupote, Vu |
| 11.4. Test Results | ore. Yun |
| 12.1. Test Specification | shotek Anbo k k kotek |
| 12.1. Test Specification | " rek Vipole, Vin |
| 12.3 Test Procedure | |
| 12.4. Test Results | Anbo, K Potek Vulpay |
| 13. Power Frequency Magnetic Field Immunity Test | k Anbote, Ans |
| 13.1. Test Specification | stek subotek Aubo sk |
| 13.1. Test Specification | ak notek Anbote |
| 13.3. Test Procedure | nbote Andotek |
| 13.4. Test Results | anbotek Anbo ak botek |
| 14 Voltage Dips and Interruptions Immunity Test | -hotek Anbots Am |
| 14.1 Test Specification | And Andores And |
| 14.2 Test Setup | Anti Jk Hotek Ant |
| 13.2. Test Setup | tek Anbor Arek |
| 14.4 Test Results | stek Anbotes Ante |
| APPENDIX I TEST SETUP PHOTOGRAPH | ok botek Anbote |
| APPENDIX II EXTERNAL PHOTOGRAPH | Anbor An rek anbore |
| APPENDIX II EXTERNAL PHOTOGRAPH | Anbores Anos ak wore |





Report No.: 18230EC20193501 Page 4 of 58

TEST REPORT

Applicant Shenzhen JHC Technology Development Co., LTD

Manufacturer Shenzhen JHC Technology Development Co., LTD

Product Name Industrial Embedded Computer

Test Model No. KMDA-2630-T001

KMDA-2630-T002, KMDA-2630-T003, KMDA-2630-T004,

KMDA-2630-S001, KMDA-2630-S002, KMDA-2630-S003, Reference Model No.

KMDA-2630-S004

JHCTECH Trade Mark

Input: DC 12.0V 1.51A 18.12W Rating(s)

EN 55032: 2015+A1:2020; Test Standard(s)

EN IEC 61000-3-2: 2019/A1:2021; EN 61000-3-3: 2013+A1:2019+A2:2021;

EN 55035: 2017+A11:2020:

(IEC 61000-4-2; IEC 61000-4-3; IEC 61000-4-4;

IEC 61000-4-5; IEC 61000-4-6; IEC 61000-4-8; IEC 61000-4-11)

The device described above is tested by Shenzhen Anbotek Compliance Laboratory Limited to determine the maximum emission levels emanating from the device and the severe levels of the device can endure and its performance criterion. The measurement results are contained in this test report and Shenzhen Anbotek Compliance Laboratory Limited is assumed full of responsibility for the accuracy and completeness of these measurements. Also, this report shows that the EUT (Equipment Under Test) is technically compliant with the EN 55032, EN IEC 61000-3-2, EN 61000-3-3, EN 55035 requirements.

This report applies to above tested sample only and shall not be reproduced in part without written approval of Shenzhen Anbotek Compliance Laboratory Limited.

| Date of Receipt: | Aug. 04, 2022 |
|-------------------------------|---------------------------------|
| Date of Test: | Aug. 04~Sept. 07, 2022 |
| | Anbotek Anbotek Anbotek Anbotek |
| Prepared By: | We Zeng |
| | (We Zeng) |
| | (ingkong)in |
| Approved & Authorized Signer: | And And And And And Andrei |
| botek Anbors An otek Anbotes | (KingKong Jin) |









Report No.: 18230EC20193501 Page 5 of 58

1. General Information

1.1. Client Information

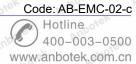
| Applicant | : Shenzhen JHC Technology Development Co., LTD |
|--------------|--|
| Address | B Area, 3rd floor, A Block Junxiangda Building, N0.9 Zhongshanyuan Road, Nanshan Distr., Shenzhen, China |
| Manufacturer | : Shenzhen JHC Technology Development Co., LTD |
| Address | B Area, 3rd floor, A Block Junxiangda Building, N0.9 Zhongshanyuan Road, Nanshan Distr., Shenzhen, China |
| Factory | : Shenzhen JHC Technology Development Co., LTD |
| Address | B Area, 3rd floor, A Block Junxiangda Building, N0.9 Zhongshanyuan Road, Nanshan Distr., Shenzhen, China |

1.2. Description of Device (EUT)

| Product Name | : | Industrial Embedded Computer |
|------------------------|---|---|
| Test Model No. | : | KMDA-2630-T001 |
| Reference Model No. | : | KMDA-2630-T002, KMDA-2630-T003, KMDA-2630-T004, KMDA-2630-S001, KMDA-2630-S002, KMDA-2630-S003, KMDA-2630-S004 (Note: All samples are the same except the model number & appearance, so we prepare "KMDA-2630-T001" for test only.) |
| Trade Mark | : | JHCTECH Anbotek Anbotek Anbotek Anbotek Anbotek |
| Test Power Supply | : | AC 230V, 50Hz |
| Test Sample No. | : | 1-1-100tek Anbotek Anbotek Anbotek Anbotek Anbotek Anbotek |
| Product Description | : | Adapter 1 MODEL: KPL-060F-VI INPUT: 100-240V~ 50/60Hz 1.7A OUTPUT: +12.0V==5.0A 60.0W Adapter 2 MODEL NO.: FSP060-DBAB1 INPUT: 100-240V~, 1.5A, 50-60Hz OUTPUT: 12.0V==5.0A MAX (60W MAX) |

Remark: (1) For a more detailed features description, please refer to the manufacturer's specifications or the User's Manual.









Report No.: 18230EC20193501 Page 6 of 58

1.3. Auxiliary Equipment Used During Test

| | - 10 AM |
|-------|-----------------------------------|
| : N | Manufacturer: PHILIPS |
| : N | M/N: 273V7QDSBF/93 |
| | S/N: UK0A2120004629A2K |
| l l | nput: AC100-240~50/60Hz 1.6A |
| : N | Manufacturer: AOC |
| : 9 | M/N: LV273HUPR |
| | S/N: APMM79A00124 7Q |
| Ĭ | nput: 100-240~50/60Hz 1.5A |
| : N | Manufacturer: DELL |
| N | M/N: SK-8120 |
| | S/N: CN-0DJ365-71616-49J-0MVR-A00 |
| l l | nput Rating: DC 5V, 0.05A |
| | CE, FCC, VCCI, KCC, TUV-GS |
| 1 | Cable: 1.8m, unshielded |
| N | Manufacturer: DELL |
| N | M/N: MS111-T |
| NS. | S/N: CN-0KW2YH-71616-488-1CBJ |
| ı | nput Rating: DC 5V, 0.1A |
| - 3 | Cable: 1.8m, unshielded |
| | CE, FCC, VCCI, KCC, TUV-GS |
| | |



Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China.

Tel:(86) 0755-26066440 Fax:(86) 0755-26014772 Email:service@anbotek.com



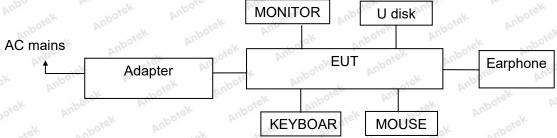
Report No.: 18230EC20193501

Page 7 of 58

1.4. Description of Test Mode

| Pretest Mode | Description | | |
|--------------|--|--|--|
| Mode 1 | botek Anbotek On Anbotek Anbotek Anbotek | | |

For Mode 1 Block Diagram of Test Setup



1.5. Test Summary

| Test Items | Test Mode | Status |
|--|---------------|---------------------------|
| Power Line Conducted Emission Test | Mode 1 | botek P Anbu |
| Asymmetric Mode Conducted Emission at Telecom Port | Mode 1 | Anbore P Anb |
| Radiated Emission Test (Below 1 GHz) | Mode 1 | Anbai Pek |
| Radiated Emission Test (Above 1GHz) | Mode 1 | ek Potek |
| Harmonic Current Test | Anbotek Anbo | otek N _{Anbotek} |
| Voltage Fluctuations & Flicker Test | Mode 1 | anbotek P Anbote |
| Electrostatic Discharge Immunity Test | Mode 1 | Anbotek Ant |
| RF Field Strength Immunity Test | Mode 1 | Anb P |
| Electrical Fast Transient/Burst Immunity Test | Mode 1 | P P Portok |
| Surge Immunity Test | Mode 1 | ofer Panber |
| Injected Currents Susceptibility Test | Mode 1 | unbore P Ame |
| Power frequency Magnetic Field Immunity Test | upotek Mootek | Anbo Ne |
| Voltage Dips and Interruptions Immunity Test | Mode 1 | k Potek |
| P) Indicates "PASS". | Aupoter Aupo | otek Anbotek |

- F) Indicates "Fail".
- N) Indicates "Not applicable".

Shenzhen Anbotek Compliance Laboratory Limited





Report No.: 18230EC20193501 Page 8 of 58

1.6. Test Equipment List

| Item | Equipment | Manufacturer | Model No. | Serial No. | Last Cal. | Cal. Interval |
|-------------|---|-------------------------|-----------|------------------|---------------|---------------|
| An' | L.I.S.N. Artificial Mains Network | Rohde & Schwarz | ENV216 | 100055 | Oct. 22, 2021 | 1 Year |
| botek 2. | Three Phase V-type Artificial Power Network | CYBERTEK | EM5040DT | E215040D T001 | Jul. 05, 2022 | 1 Year |
| 3. | EMI Test Receiver | Rohde & Schwarz | ESCI | 100627 | Oct. 22, 2021 | 1 Year |
| 4. | RF Switching Unit | Compliance Direction | RSU-M2 | 38303 | Oct. 22, 2021 | 1 Year |
| 5 | Software Name EZ-EMC | Ferrari Technology | ANB-03A | N/A | N/A | N/A |

| Item | Equipment | Manufacturer | Model No. | Serial No. | Last Cal. | Cal. Interval |
|-----------------|---|-------------------------|-----------|------------------|---------------|---------------|
| 1. 1 | ISN | Schwarzbeck | NTFM 8158 | #172 | Oct. 22, 2021 | 1 Year |
| 2. | EMI Test Receiver | Rohde & Schwarz | ESCI | 100627 | Oct. 22, 2021 | 1 Year |
| 3. | RF Switching Unit | Compliance Direction | RSU-M2 | 38303 | Oct. 22, 2021 | 1 Year |
| 4. _b | Software Name EZ-EMC | Ferrari Technology | ANB-03A | N/A | N/A | N/A |
| 5. | Three Phase V-type Artificial Power Network | CYBERTEK | EM5040DT | E215040D T001 | Jul 05, 2022 | 1 Year |

□ Radiated Emission Test (Below 1 GHz)

| Item | Equipment | Manufacturer | Model No. | Serial No. | Last Cal. | Cal. Interval |
|--------------|----------------------------|--------------------|-----------|------------------|---------------|---------------|
| 1. | EMI Test Receiver | Rohde & Schwarz | ESR26 | 101481 | Oct. 22, 2021 | 1 Year |
| 2. | Pre-amplifier | SONOMA | 310N | 186860 | Oct. 22, 2021 | 1 Year |
| 3. | Bilog Broadband Antenna | Schwarzbeck | VULB9163 | VULB 9163-289 | Oct. 22, 2021 | 2 Year |
| nbotek 4. | Software Name EZ-EMC | Ferrari Technology | ANB-03A | N/A | N/A | N/A |

Code: AB-EMC-02-c
Hotline
400-003-0500





Report No.: 18230EC20193501 Page 9 of 58

□ Radiated Emission Test (Above 1GHz)

| Item | Equipment | Manufacturer | Model No. | Serial No. | Last Cal. | Cal. Interval |
|------|-------------------------------|-------------------------|----------------|------------------|---------------|---------------|
| 1. | EMI Test Receiver | Rohde & Schwarz | ESR26 | 101481 | Oct. 22, 2021 | 1 Year |
| 2. | Bilog Broadband Antenna | Schwarzbeck | VULB9163 | VULB 9163-289 | Oct. 22, 2021 | 2 Year |
| 3. | Pre-amplifier | SONOMA | 310N | 186860 | Oct. 22, 2021 | 1 Year |
| 4. | Software Name EZ-EMC | Ferrari Technology | ANB-03A | N/A | N/A | N/A |
| 5. | Preamplifier | SKET Electronic | BK1G18G30 D | KD17503 | Oct. 22, 2021 | 1 Year |
| 6. | Double Ridged Horn Antenna | Instruments corporation | GTH-0118 | 351600 | Oct. 22, 2021 | 2 Year |

| Item Equipment | | Manufacturer | Model No. | Serial No. | Last Cal. | Cal. Interval |
|------------------|----------------------------------|--------------|--------------------|------------|---------------|---------------|
| ooter 1. oter | Programmable AC Power source | IVYTECH | APS-5005A | 632734 | Oct. 22, 2021 | 1 Year |
| 2.00 | Harmonic and Flicker Analyzer | EMC-PARTNER | HMONICS 1000-1P | 164 | Oct. 22, 2021 | 1 Year |
| 3. | Harmonics-1000 | N/A | Ed.3.0+4.0 | bote N.A M | N/A | N/A MOO |

| Item | Equipment | Manufacturer | Model No. | Serial No. | Last Cal. | Cal. Interval |
|--------|----------------|--------------|------------|------------|---------------|---------------|
| And 1. | ESD Simulators | emtest | ESD NX30.1 | 11936 | Mar. 25, 2022 | 1 Year |

⊠ RF Field Strength Immunity Test

| ltem | Equipment | Manufacturer | Model No. | Serial No. | Last Cal. | Cal. Interval |
|--------------------|-------------------------------------|-------------------------|---------------------|----------------|---------------|---------------|
| _{ot} e1. | Signal Generator | Agilent | N5182A | MY4818065 6 | Oct. 22, 2021 | 1 Year |
| nb2.ek | Amplifier | Micotoop | MPA-80-100 0-250 | MPA190309 6 | Oct. 22, 2021 | 1 Year |
| 3. | Amplifier | c above Average | | MPA190312 2 | Oct. 22, 2021 | 1 Year |
| 4. ^{A.n.} | Log-Periodic Antenna Schwarzbeck | | VULP9118E | 00992 N/A | | N/A |
| 5. | Horn Antenna | Instruments corporation | GTH-0118 | 351600 | Oct. 22, 2021 | 2 Year |
| 6. | Power Sensor | Agilent | E9301A | MY4149890 6 | Oct. 22, 2021 | 1 Year |
| Allooke | Power Sensor | Agilent | E9301A | MY4149808 8 | Oct. 22, 2021 | 1 Year |
| 1048 | Power Meter Agilent | | E4419B | GB4020290 9 | Oct. 22, 2021 | 1 Year |
| 9. | Electric field Probe | Narda | EP 601 | 811ZX10351 | Oct. 22, 2021 | 1 Year |
| 10 . | RS Test software | EMtrace | EM 3 | V1.1.7 | N/A | N/A |

Shenzhen Anbotek Compliance Laboratory Limited





Report No.: 18230EC20193501 Page 10 of 58

☑ Electrical Fast Transient/Burst Immunity Test

| Item | Equipment | Manufacturer | Model No. | Serial No. | Last Cal. | Cal. Interval |
|------|----------------------------|--------------|-----------|------------|---------------|---------------|
| 1. | Surge Generator | TESEQ | NSG 3060 | 1480 | Oct. 22, 2021 | 1 Year |
| 2. | CDN _M to of the | TESEQ | CDN 3061 | 1408 | Oct. 22, 2021 | 1 Year |
| 3. | EFT-Clamp | PRIMA | EFT-Clamp | Aupor / A | Oct. 22, 2021 | 1 Year |

⊠ Surge Immunity Test

| Item | Equipment | Manufacturer | Model No. | Serial No. | Last Cal. | Cal. Interval | |
|------|------------------------------|--------------|----------------------------|------------|--------------------|---------------|--|
| 1. | Surge Generator | TESEQ | ESEQ NSG 3060 | | 1480 Oct. 22, 2021 | | |
| 2. | CDN | TESEQ | CDN 3061 1408 Oct. 22, 202 | | Oct. 22, 2021 | 1 Year | |
| 3. | Telecom port surge generator | PMI | TW101 | 190411 | May 13, 2022 | 1 Year | |

⊠ Injected Currents Susceptibility Test

| Item | Equipment | Manufacturer | Model No. | Serial No. | Last Cal. | Cal. Interval | |
|-----------------|--|--------------|------------------|-------------------|---------------|---------------|--|
| 1. A | C/S Conducted Immunity Test System | FRANKONIA | CIT-10 126A1196/ | | Oct. 22, 2021 | 1 Year | |
| o*2. | CDN | FRANKONIA | CDN - M2+ M3 | A2210178/20 12 | Oct. 22, 2021 | 1 Year | |
| 10 3. | 6dB Attenuator | FRANKONIA | DAM 26W | 1172202 | Oct. 22, 2021 | 1 Year | |
| 4.00 | CIT-10 | FRANKONIA | Version1.1.7 | N/A | N/A | N/A | |
| 5. ^Δ | EM-Clamp | FRANKONIA | EMCL-20 | 18101728-01 03 | May 17,2022 | 1 Year | |

☐ Power frequency Magnetic Field Immunity Test

| Item | Equipment | Manufacturer | Model No. | Serial No. | Last Cal. | Cal. Interval |
|-------|--|--------------|-----------------|------------|---------------|---------------|
| Anbo' | Power Frequency Magnetic Field Generator | EVERFINE | EMS61000-8 K | 906002 | Oct. 22, 2021 | 1 Year |

⊠ Voltage Dips and Interruptions Immunity Test

| Item | Equipment | Manufacturer | Model No. | Serial No. | Last Cal. | Cal. Interval |
|-------|------------------------|--------------|----------------|------------|---------------|---------------|
| Arbot | CYCLE SAG Simulator | PRIMA | DRP61011A G | PR12046234 | Oct. 22, 2021 | 1 Year |

Shenzhen Anbotek Compliance Laboratory Limited

Code: AB-EMC-02-c
Hotline
400-003-0500





Report No.: 18230EC20193501 Page 11 of 58

1.7. Description of Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

FCC-Registration No.: 184111

Shenzhen Anbotek Compliance Laboratory Limited, EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration No. 184111.

ISED-Registration No.: 8058A

Shenzhen Anbotek Compliance Laboratory Limited, EMC Laboratory has been registered and fully described in a report filed with the (ISED) Innovation, Science and Economic Development Canada. The acceptance letter from the ISED is maintained in our files. Registration 8058A.

Test Location

Shenzhen Anbotek Compliance Laboratory Limited.

1/F, Building D, Sogood Science and Technology Park, Sanwei community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China.518128





Report No.: 18230EC20193501 Page 12 of 58

1.8. EMS Performance Criteria

Performance criterion A

The equipment shall continue to operate as intended without operator intervention. No degradation of performance, loss of function or change of operating state is allowed below a performance level specified by the manufacturer when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

Performance criterion B

During the application of the disturbance, degradation of performance is allowed. However, no unintended change of actual operating state or stored data is allowed to persist after the test.

After the test, the equipment shall continue to operate as intended without operator intervention; no degradation of performance or loss of function is allowed, below a performance level specified by the manufacturer, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.

If the minimum performance level (or the permissible performance loss), or recovery time, is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

Performance criterion C

Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions. A reboot or re-start operation is allowed.

Information stored in non-volatile memory, or protected by a battery backup, shall not be lost.







Report No.: 18230EC20193501 Page 13 of 58

2. Power Line Conducted Emission Test

2.1. Test Standard and Limit

| 4 | Test Standard: | | EN 55032 | V Ant | rotek o | Anbotek | Aupore. | Pur |
|---|----------------|-----|----------|-------|------------|---------|---------|-----|
| | V 10' | D/. | - 14 | 0. | VVD. | | ~0, | 565 |

□ Limits for conducted emission at the AC mains power ports of Class A equipment

| Frequency (MHz) | Limits (dBμV) | | | | | |
|-----------------|------------------|---------------|--|--|--|--|
| Frequency (MHz) | Quasi-peak Level | Average Level | | | | |
| 0.15 ~ 0.50 | 79.0 | 66.0 | | | | |
| 0.50 ~ 30.00 | 73.0 | 60.0 dek | | | | |

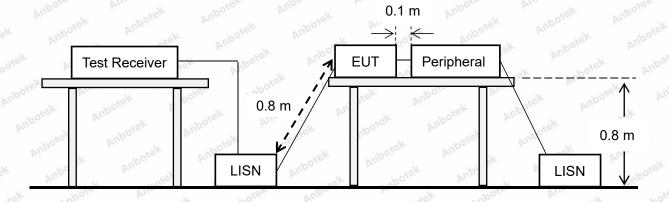
☐ Limits for conducted emission at the AC mains power ports of Class B equipment

| Fraguency (MHz) | Limits (| dBμV) | | |
|-----------------|------------------|------------------------|--|--|
| Frequency (MHz) | Quasi-peak Level | Average Level | | |
| 0.15 ~ 0.50 | 66.0 ~ 56.0 * | 56.0 ~ 46.0 * | | |
| 0.50 ~ 5.00 | 56.0 | 46.0 | | |
| 5.00 ~ 30.00 | 60.0 | stek Anbore 50.0 Anbor | | |

Remark:

- (1) The lower limit shall apply at the transition frequencies.
- (2) The limit decreases linearly with the logarithm of the frequency in the range 0.15MHz to 0.50MHz.

2.2. Test Setup







Report No.: 18230EC20193501 Page 14 of 58

2.3. Test Procedure

The table-top EUT is placed on a non-conductive table 0.8 m above the horizontal ground reference plane, and the back of the EUT is 0.4 m away from the vertical ground reference plane, and at least 0.8 m from any other metal surface or ground plane. The floor-standing EUT is placed on an insulating support 0.1 m above the horizontal ground reference plate, at least 0.8 m away from other metal objects.

Connect EUT to the power mains through an LISN. Where the mains cable supplied by the manufacturer is longer than 1 m, the excess should be folded at the center into a bundle no longer than 0.4 m, so that its length is shortened to 1 m. All the peripherals are connecting to the other LISN.

The initial testing identified the frequency that has the highest disturbance relative to the limit while operating the EUT in typical modes of operation and cable positions in a test setup representative of typical system configuration.

The identification of the frequency of highest disturbance with respect to the limit was found by investigating disturbances at a number of significant frequencies. The probable frequency of maximum disturbance had been found and that the associated cable and EUT configuration and mode of operation had been identified.

Set the test-receiver to quasi peak detect function and average detect function, and to measure the conducted emissions values.

2.4. Test Results

PASS

The test curves are shown in the following pages.







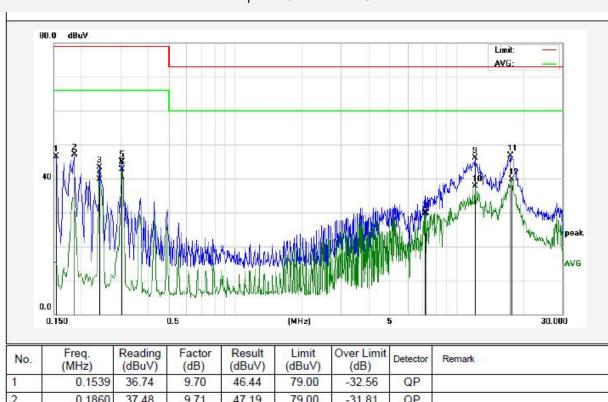
Page 15 of 58 Report No.: 18230EC20193501

Power Line Conducted Test Data

Test Site: 1# Shielded Room Test Specification: AC 230V, 50Hz

Comment: Live Line

Temp.: 22.8℃ Hum.: 48%



| No. | Freq. (MHz) | Reading (dBuV) | Factor (dB) | Result (dBuV) | Limit (dBuV) | Over Limit (dB) | Detector | Remark |
|-----|----------------|-------------------|----------------|------------------|-----------------|--------------------|----------|--------|
| 1 | 0.1539 | 36.74 | 9.70 | 46.44 | 79.00 | -32.56 | QP | |
| 2 | 0.1860 | 37.48 | 9.71 | 47.19 | 79.00 | -31.81 | QP | |
| 3 | 0.2420 | 33.66 | 9.71 | 43.37 | 79.00 | -35.63 | QP | |
| 4 | 0.2420 | 30.06 | 9.71 | 39.77 | 66.00 | -26.23 | AVG | |
| 5 | 0.3060 | 35.08 | 9.73 | 44.81 | 79.00 | -34.19 | QP | |
| 6 | 0.3060 | 33.01 | 9.73 | 42.74 | 66.00 | -23.26 | AVG | |
| 7 | 7.1380 | 19.97 | 9.78 | 29.75 | 60.00 | -30.25 | AVG | |
| 8 | 7.2620 | 19.97 | 9.79 | 29.76 | 60.00 | -30.24 | AVG | |
| 9 | 12.0980 | 36.21 | 9.90 | 46.11 | 73.00 | -26.89 | QP | |
| 10 | 12.0980 | 27.77 | 9.90 | 37.67 | 60.00 | -22.33 | AVG | 2 |
| 11 | 17.5100 | 36.68 | 10.06 | 46.74 | 73.00 | -26.26 | QP | |
| 12 | 17.8140 | 29.70 | 10.07 | 39.77 | 60.00 | -20.23 | AVG | |

Note: Result = Reading + Factor Over Limit = Result - Limit







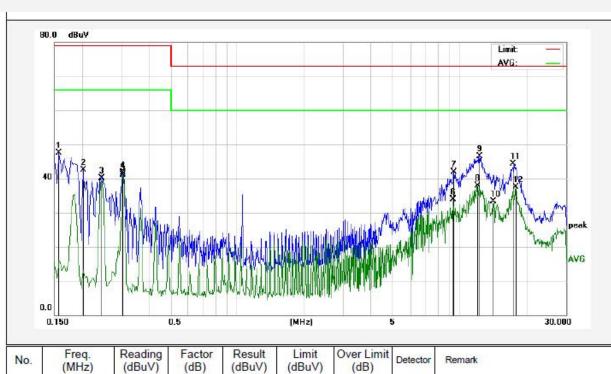


Report No.: 18230EC20193501 Page 16 of 58

Power Line Conducted Test Data

Test Site: 1# Shielded Room
Test Specification: AC 230V, 50Hz
Comment: Neutral Line

Temp.: 22.8℃ Hum.: 48%



| No. | Freq. (MHz) | Reading (dBuV) | Factor (dB) | Result (dBuV) | Limit (dBuV) | Over Limit (dB) | Detector | Remark |
|-----|----------------|-------------------|----------------|------------------|-----------------|--------------------|----------|--------|
| 1 | 0.1580 | 37.84 | 9.70 | 47.54 | 79.00 | -31.46 | QP | |
| 2 | 0.2020 | 32.72 | 9.71 | 42.43 | 79.00 | -36.57 | QP | |
| 3 | 0.2460 | 30.42 | 9.71 | 40.13 | 66.00 | -25.87 | AVG | |
| 4 | 0.3060 | 31.97 | 9.73 | 41.70 | 79.00 | -37.30 | QP | |
| 5 | 0.3060 | 31.32 | 9.73 | 41.05 | 66.00 | -24.95 | AVG | |
| 6 | 9.3100 | 24.02 | 9.82 | 33.84 | 60.00 | -26.16 | AVG | |
| 7 | 9.4300 | 31.99 | 9.82 | 41.81 | 73.00 | -31.19 | QP | |
| 8 | 11.9780 | 27.95 | 9.89 | 37.84 | 60.00 | -22.16 | AVG | |
| 9 | 12.2739 | 36.70 | 9.90 | 46.60 | 73.00 | -26.40 | QP | |
| 10 | 14.1540 | 23.41 | 9.96 | 33.37 | 60.00 | -26.63 | AVG | |
| 11 | 17.4500 | 34.16 | 10.05 | 44.21 | 73.00 | -28.79 | QP | |
| 12 | 17.8779 | 27.42 | 10.07 | 37.49 | 60.00 | -22.51 | AVG | |

Note: Result = Reading + Factor Over Limit = Result - Limit







Report No.: 18230EC20193501 Page 17 of 58

3. Asymmetric Mode Conducted Emission at Telecom Port

3.1. Test Standard and Limit

| | 011 | -01 | ~0 | | 14 | 1-07 | Dilla | 200 | 200 |
|---|--------|----------|----|----------|-------|------|---------|-------|-----|
| K | Test S | Standard | 0 | EN 55032 | N. C. | Ann- | Anbotek | Aupo. | br. |
| | | | | | | | | | |

| Fraguenov (MHz) | Limits (dBμV) | | | | | | | |
|-----------------|------------------|---------------|--|--|--|--|--|--|
| Frequency (MHz) | Quasi-peak Level | Average Level | | | | | | |
| 0.15 ~ 0.50 | 97.0 ~ 87.0 * | 87.0 ~ 74.0 * | | | | | | |
| 0.50 ~ 30.00 | 87.0 | 74.0 | | | | | | |

Remark:

The limit decreases linearly with the logarithm of the frequency in the range 0.15MHz to 0.50MHz.

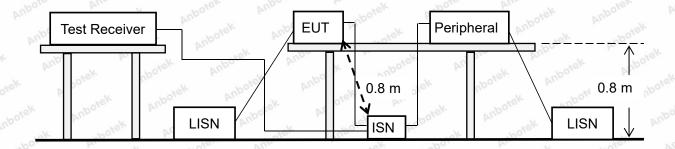
☐ Limits for asymmetric mode conducted emissions of Class B equipment

| Fraguency (MHz) | Limits | Limits (dBμV) | | | | | | |
|-----------------|------------------|---------------|--|--|--|--|--|--|
| Frequency (MHz) | Quasi-peak Level | Average Level | | | | | | |
| 0.15 ~ 0.50 | 84.0 ~ 74.0 * | 74.0 ~ 44.0 * | | | | | | |
| 0.50 ~ 30.00 | 74.0 | 64.0 Andrew | | | | | | |

Remark:

The limit decreases linearly with the logarithm of the frequency in the range 0.15MHz to 0.50MHz.

3.2. Test Setup









Report No.: 18230EC20193501 Page 18 of 58

3.3. Test Procedure

The table-top EUT is placed on a non-conductive table 0.8 m above the horizontal ground reference plane, and the back of the EUT is 0.4 m away from the vertical ground reference plane, and at least 0.8 m from any other metal surface or ground plane. The floor-standing EUT is placed on an insulating support 0.1 m above the horizontal ground reference plane, at least 0.8 m away from other metal objects.

Connect EUT to the power mains through an LISN. Where the mains cable supplied by the manufacturer is longer than 1 m, the excess should be folded at the center into a bundle no longer than 0.4 m, so that its length is shortened to 1 m. All the peripherals are connecting to the other LISN.

The EUT was connected to the peripheral equipment through the ISN and linked in normal condition.

Set the test-receiver to quasi peak detect function and average detect function, and to measure the asymmetric mode conducted emission values.

3.4. Test Results

PASS

The test curves are shown in the following pages.





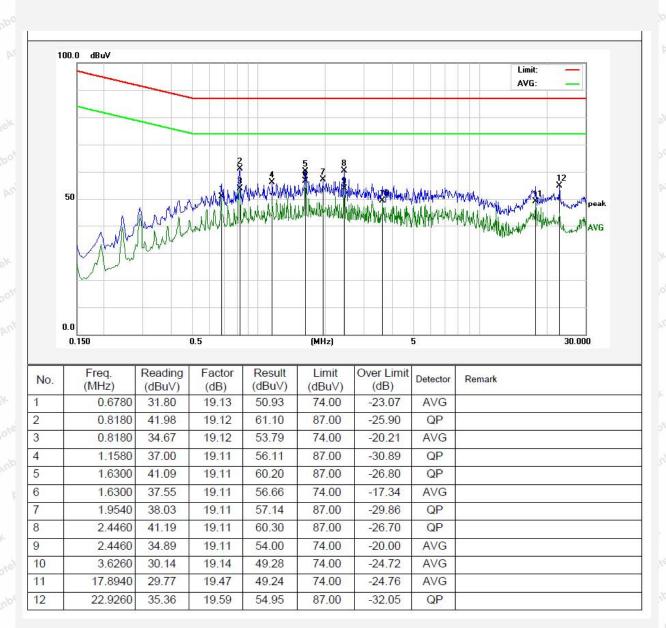


Report No.: 18230EC20193501 Page 19 of 58

Asymmetric Mode Conducted Emission Test Data

Test Site: 1# Shielded Room
Test Specification: AC 230V, 50Hz
Comment: Telecom Port

Temp.: 22.8℃ Hum.: 48%



Note: Result = Reading + Factor Over Limit = Result - Limit







Report No.: 18230EC20193501 Page 20 of 58

4. Radiated Emission Test (Below 1 GHz)

4.1. Test Standard and Limit

| | Dille | -81 | 200 | 200 | 14 | 1-01 | Diller | 201 | 200 |
|----|--------|----------|-----|----------|------|------|---------|-------|-----|
| N. | Test S | Standard | 60 | EN 55032 | yer. | Ann | Anbotek | Anbo. | br. |
| | | | | | | | | | |

□ Limit for radiated emissions at frequencies up to 1 GHz for class A equipment

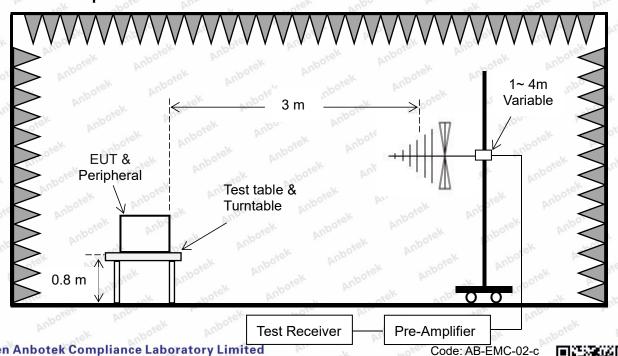
| | Frequency | | | Distance | e | Field Strengths Limit | | | |
|--------|------------|---------|--------|----------|---------|-----------------------|----|---------|--|
| | (MHz) | | | (Meters |) | (dBμV/m) | | | |
| Aupole | 30 ~ 230 | Anbotel | Anbo | 3 | Anbotek | Aupole | 50 | Anbotek | |
| Anbo | 230 ~ 1000 | Anbo | Helt M | 3 | nbotek | Aupole | 57 | Anbo | |

Limit for radiated emissions at frequencies up to 1 GHz for class B equipment

| Frequency (MHz) | | | | Distance (Meters | | Field Strengths Limit (dBμV/m) | | |
|--------------------|------------|---------|-----------|---------------------|-------|--------------------------------|--------------|------|
| 8/K | 30 ~ 230 | · ok Þu | botek | Anbotak | Anbo | Anbotek | 40 | Pur |
| otek | 230 ~ 1000 | or sek | an abotek | An'3° ren | K WUS | ek Anbore | 47 Anboratek | . bo |

Remark: The lower limit shall apply at the transition frequencies.

4.2. Test Setup



Shenzhen Anbotek Compliance Laboratory Limited

400-003-0500 www.anbotek.com.cr





Report No.: 18230EC20193501 Page 21 of 58

4.3. Test Procedure

The table-top EUT is placed on a non-conductive table 0.8 m above the horizontal ground reference plane. The floor-standing EUT is placed on an insulating support 0.1 m above the horizontal ground reference plane.

The EUT was set 3 m away from the receiving antenna that was mounted on a non-conductive mast. The antenna can move up and down between 1 to 4 m to find out the maximum emission level.

The turntable can rotate 360 degree to determine the position of the maximum emission level.

The initial testing identified the frequency that has the highest disturbance relative to the limit while operating the EUT in typical modes of operation and cable positions in a test setup representative of typical system configuration.

The identification of the frequency of highest emission with respect to the limit was found by investigating emissions at a number of significant frequencies. The probable frequency of maximum emission had been found and that the associated cable and EUT configuration and mode of operation had been identified.

The bandwidth of the Receiver is set at 120 kHz

4.4. Test Results

PASS

The test curves are shown in the following pages.







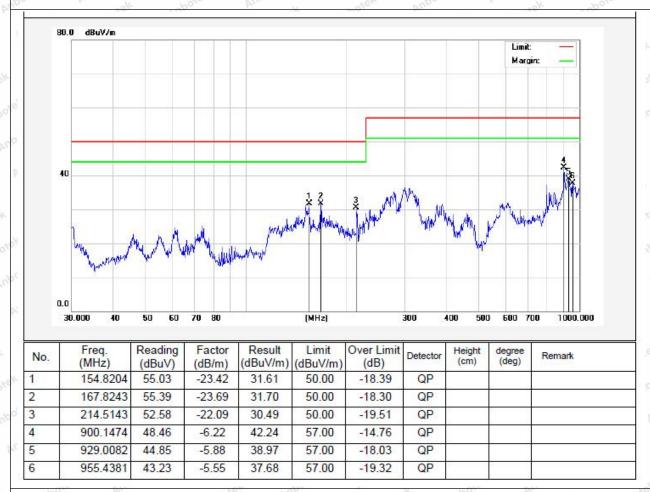
Report No.: 18230EC20193501 Page 22 of 58

Test item: Radiation Test Polarization: Horizontal

Standard: (RE)EN 55032 Power Source: AC 230V, 50Hz

Frequency Range: 30MHz ~ 1000MHz Temp.($^{\circ}$)/Hum.($^{\circ}$ RH): 24.5($^{\circ}$)/50%RH

Distance: 3m



Note: Result= Reading + Factor Over Limit=Result-Limit









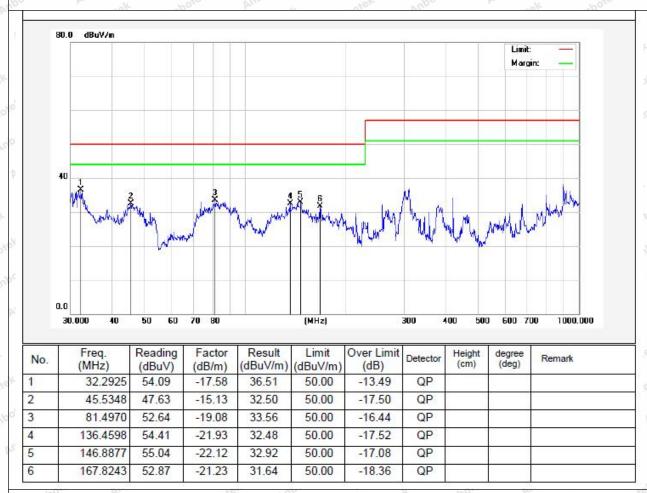
Report No.: 18230EC20193501 Page 23 of 58

Test item: Radiation Test Polarization: Vertical

Standard: (RE)EN 55032 Power Source: AC 230V, 50Hz

Frequency Range: 30MHz ~ 1000MHz Temp.($^{\circ}$)/Hum.($^{\circ}$ RH): 24.5($^{\circ}$)/50%RH

Distance: 3m



Note: Result= Reading + Factor Over Limit=Result-Limit









Report No.: 18230EC20193501 Page 24 of 58

5. Radiated Emission Test (Above 1GHz)

Remark: The lower limit shall apply at the transition frequencies.

5.1. Test Standard and Limit

| | Ollin | 10- | ~00 | Part . | Mr. | 1-01 | D'Lean | - O.K. | 200 |
|-----|-------|------------|-----|----------|------|------|---------|--------|------|
| e/4 | Tes | t Standard | 10 | EN 55032 | | Ann | Anbotek | Anbor | Ni. |
| | | V() \ | 100 | | 6.65 | | | W 01 | 12/1 |

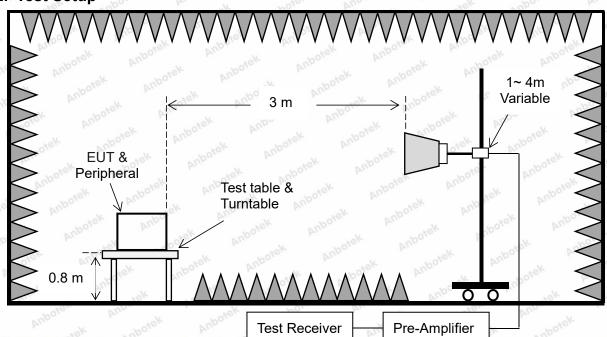
Limit for radiated emissions at frequencies above 1 GHz for class A equipment

| Frequency | Dista | ance | Field Strengths Limit (dBμV/m) | | | | | |
|------------|-----------------|-----------|--------------------------------|------------|-----------------|--------|--|--|
| (MHz) | (Met | ers) | Peak | | Average | | | |
| 1000 ~ 300 | 0 3 | Andhotek | Anbotek 76 A | upo. Itali | 56 | Aupole | | |
| 3000 ~ 600 | O Anbote Anbota | ek woodsk | 80 | Anbo | 60 ^k | Vupo, | | |

Limit for radiated emissions at frequencies above 1 GHz for class B equipment

| | Frequency | Distance | | Field Strengths Limit (dBμV/m) | | | | |
|-------|-----------------------|-----------------------|----------|--------------------------------|--------|--------------|--|--|
| | (MHz) | (Meters) | | Peak | | Average | | |
| ek | 1000 ~ 3000 | rek Napc3.k | Anbore | 70 | Anbole | 50 | | |
| ootek | 3000 ~ 6000 | 30tek | Ant | 74 | Pupo | 54 | | |
| Ren | nark: The lower limit | shall apply at the tr | ansition |) frequencies | ek A | upotek Aupor | | |

5.2. Test Setup



Shenzhen Anbotek Compliance Laboratory Limited

www.anbotek.com.cn

Code: AB-EMC-02-c Hotline.

400-003-0500



Report No.: 18230EC20193501 Page 25 of 58

5.3. Test Procedure

The table-top EUT is placed on a non-conductive table 0.8 m above the horizontal ground reference plane. The floor-standing EUT is placed on an insulating support 0.1 m above the horizontal ground reference plane.

The EUT was set 3 m away from the receiving antenna that was mounted on a non-conductive mast. The antenna can move up and down between 1 to 4 m to find out the maximum emission level.

The turntable can rotate 360 degree to determine the position of the maximum emission level.

The initial testing identified the frequency that has the highest disturbance relative to the limit while operating the EUT in typical modes of operation and cable positions in a test setup representative of typical system configuration.

The identification of the frequency of highest emission with respect to the limit was found by investigating emissions at a number of significant frequencies. The probable frequency of maximum emission had been found and that the associated cable and EUT configuration and mode of operation had been identified.

The test receiver is set to peak and average detects function

The bandwidth of the test receiver is set at 1MHz.

5.4. Test Results

PASS

The test curves are shown in the following pages.







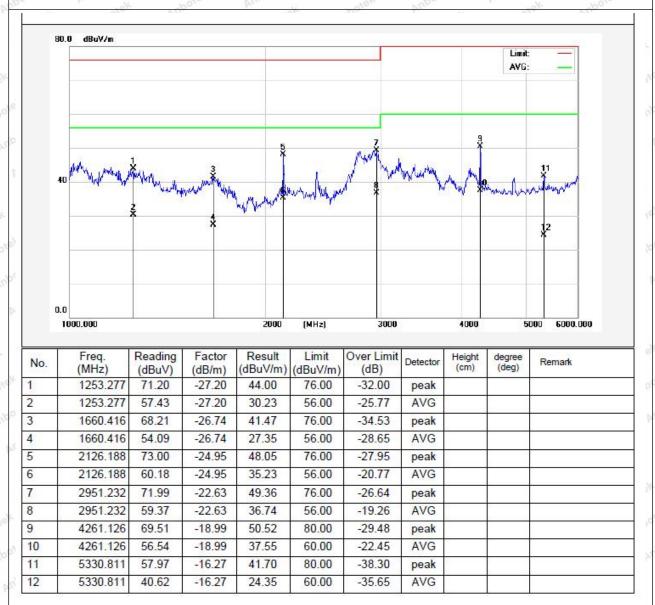
Report No.: 18230EC20193501 Page 26 of 58

Test item: Radiation Test Polarization: Horizontal

Standard: (RE)EN 55032 Power Source: AC 230V, 50Hz

Frequency Range: $1 \text{GHz} \sim 6 \text{GHz}$ Temp.($^{\circ}$ C)/Hum.($^{\circ}$ RH): $24.5(^{\circ}$ C)/50%RH

Distance: 3m



Note: Result=Reading + Factor Over Limit=Result - Limit







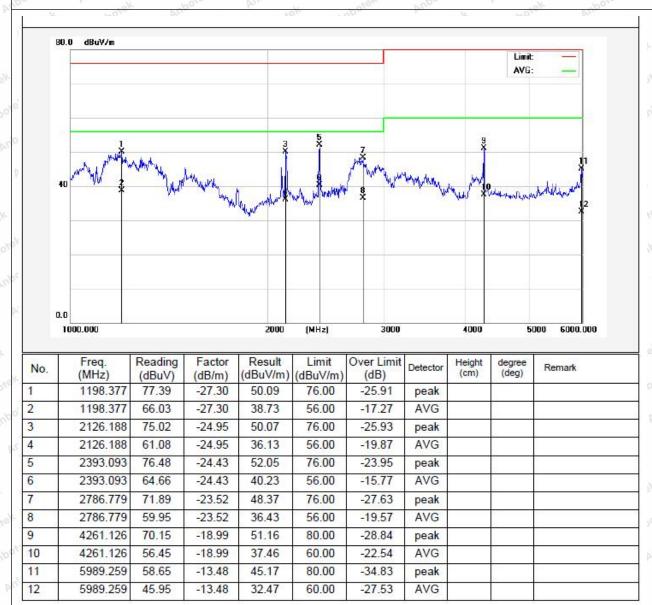
Report No.: 18230EC20193501 Page 27 of 58

Test item: Radiation Test Polarization: Vertical

Standard: (RE)EN 55032 Power Source: AC 230V, 50Hz

Frequency Range: $1 \text{GHz} \sim 6 \text{GHz}$ Temp.(°C)/Hum.(%RH): 24.5(°C)/50%RH

Distance: 3m



Note: Result=Reading + Factor Over Limit=Result - Limit







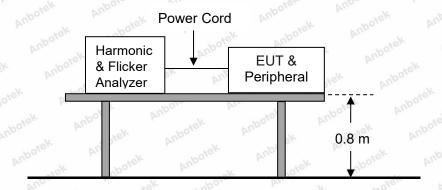
Report No.: 18230EC20193501 Page 28 of 58

6. Harmonic Current Test

6.1. Test Standard

| Test Standard: | EN IEC 61000-3-2 | Anbo | hotek | Aupolo | V. |
|--------------------|------------------|-------|-------|--------|-------|
| root otaridara. | 2111200100002 | 10101 | VUD | Yes | - 4po |

6.2. Test Setup



6.3. Test Procedure

The table-top EUT is placed on the top of a wooden table 0.8 m above the ground (0.1 m for the floor-standing EUT) and operated to produce the maximum harmonic components under normal operating conditions for each successive harmonic component in turn. The correspondent test program of test instrument to measure the current harmonics emanated from EUT is chosen. The measure time shall be not less than the necessary for the EUT to be exercised.

6.4. Test Results

(The active input power of the EUT is less than 75W. Therefore, according to EN IEC 61000-3-2, no limits are necessary.)







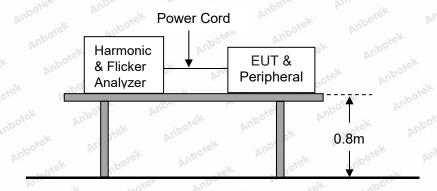
Report No.: 18230EC20193501 Page 29 of 58

7. Voltage Fluctuations & Flicker Test

7.1. Test Standard

| | Tt Ot dd- | EN 64000 0 0 | Aribo | Yes | Sport | Die |
|---|----------------|--------------|-------|-------|--------|---------|
| 4 | Test Standard: | EN 61000-3-3 | Lotek | Aupo, | W. Yek | nboth a |

7.2. Test Setup



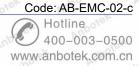
7.3. Test Procedure

The table-top EUT is placed on the top of a wooden table 0.8 m above the ground (0.1 m for the floor-standing EUT) and operated to produce the most unfavorable sequence of voltage changes under normal conditions during the flicker measurement. The observation period for short-term flicker indicator is 10 minutes and the observation period for long-term flicker indicator is 2 hours.

7.4. Test Results

PASS

The test curves are shown in the following pages.

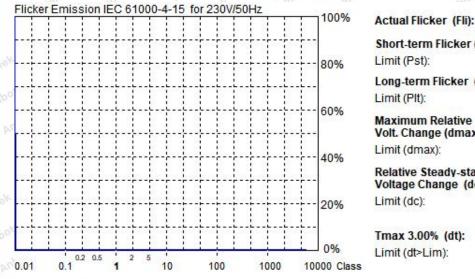






Page 30 of 58 Report No.: 18230EC20193501

Flicker Test Summary (Run time)



0.00 Short-term Flicker (Pst): 0.07 1.00 0.00 Long-term Flicker (Plt): 0.65

Maximum Relative Volt. Change (dmax): 0.00% 4.00%

Relative Steady-state Voltage Change (dc): 0.03% 3.00%

Tmax 3.00% (dt): 0.00ms 200ms

Flicker Emission - IEC 61000-3-3, EN 61000-3-3

P = 14.97 Urms = 229.5 V Irms = 0.166 pf = 0.393

Range: V-nom: 230 V

Test aborted, Result: PASSED

HAR-1000 EMC-Part

Full Bar : Actual Values **Empty Bar: Maximum Values** Circles : Average Values

Blue: Current, Green: Voltage, Red: Failed

Urms = 229.5V Freq = 50.000 Range: Irms = lpk 5.824 0.166A 0.967A cf S 0.393 14.97W 38.10VA pf

 $10 \times 1min = 10min (100 \%)$ Test - Time :

LIN (Line Impedance Network): L: 0.24ohm +j0.15ohm N: 0.16ohm +j0.10ohm

0.65 Pst 1.00 Limits : Plt

> 4.00 % 3.00 % dmax: dc dtLim: 3.00 % dt>Lim: 200ms

Test aborted, Result: PASSED

dmax dc dt>Lim [%] [%] [ms] 0.000 0.000 0.000









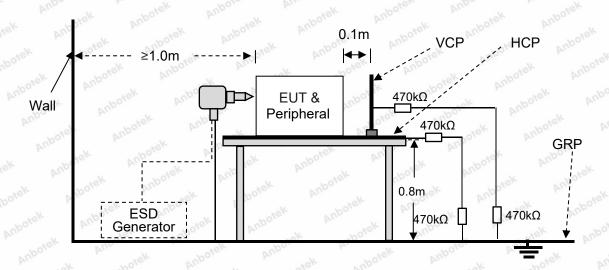
Report No.: 18230EC20193501 Page 31 of 58

8. Electrostatic Discharge Immunity Test

8.1. Test Specification

| 1/4 | Test Standard : | EN 55035 |
|-----|-----------------------|---|
| 0 | Basic standard : | IEC 61000-4-2: 2008 |
| | Performance criteria: | Bek Anbore An botek Anborek Anborek |
| ΣŢ | Test Level : | ± 8kV (Air Discharge) ± 4kV (Contact Discharge) |

8.2. Test Setup



8.3. Test Procedure

- a. In the case of air discharge testing, the climatic conditions shall be within the following ranges:
- Ambient temperature: 15°C to 35°C;
- Relative humidity: 30% to 60%;
- Atmospheric pressure: 86 kPa (860 mbar) to 106 kPa (1060 mbar)
- b. In the case of contact discharges, the tip of the discharge electrode shall touch the EUT before the discharge switch is operated.
- c. In the case of painted surface covering a conducting substrate, the following procedure shall be adopted: - If the coating is not declared to be an insulating coating by the equipment manufacturer, then the pointed tip of the generator shall penetrate the coating so as to make contact with the conducting substrate. - Coating declared as insulating by the manufacturer shall only be submitted to the air discharge. - The contact discharge test shall not be applied to such surfaces.

Shenzhen Anbotek Compliance Laboratory Limited





Report No.: 18230EC20193501

Page 32 of 58

d. In the case of air discharges, the round discharge tip of the discharge electrode shall be approached as fast as possible (without causing mechanical damage) to touch the EUT. After each discharge, the ESD generator (discharge electrode) shall be removed from the EUT. The generator is then retriggered for a new single discharge. This procedure shall be repeated until the discharges are completed. In the case of an air discharge test, the discharge switch, which is used for contact discharge, shall be closed.

- e. The test voltage shall be increased from the minimum to the selected test severity level, in order to determine any threshold of failure. The final test level should not exceed the product specification value in order to avoid damage to the equipment.
- f. The test shall be performed with both air discharge and contact discharge. The test shall be performed with single discharges. On each pre-selected point at least 10 single discharges (in the most sensitive polarity) shall be applied. For the time interval between successive single discharges an initial value of 1 s is recommended. Longer intervals may be necessary to determine whether a system failure has occurred.
- g. Ensure that the applied charge on the EUT has been dis-charged before next ESD pulse.

8.4. Test Results

PASS

Please refer to the following page.







Report No.: 18230EC20193501 Page 33 of 58

Electrostatic Discharge Test Results

| Test Result: | ⊠ Pass □ | Fail | Temper | rature: | Anbotek | 23.2℃ | 1/4 | Anbotek |
|----------------------------|----------------|------------------|--------------------|------------|--------------------------------------|---------|--------|---------------|
| Power Supply: | AC 230V, 50Hz | And | Humidit | ty: | Vupo. | 49% | orek | Anboy |
| k hotek Anbi | PUPP. | ek al | potek | Aupor | N. Direct | Lotek I | upoter | PU |
| Anbotek Anbotek Lo | ocation | ootek Anbotek | Amborek Amborek | A-Air D | ind Discharge t Dischar | 70, | Result | otek motek |
| Air discharge: ±2.0 kV, ±4 | .0 kV, ±8.0 kV | Anbotek | Co | ontact dis | charge: ± | :4.0 kV | sek l | yur Vupote |
| DC Port | rek Anbotek | points | otek A | Anbotek | A Anboi | ⊠A | В | □С |
| USB Port | botek Anbot | points | mbotek | Anbote | C VU | A Day | ⊠B | C |
| LAN Port | Anboren Ant | points | Anborek | ak Anb | C | ⊠A | □В | ПС |
| VGA Port | Anborek 4 | points | Pupo, | notek l | C Anbotek | ⊠A | □В | □C |
| HDMI Port | Anborek 4 | points | otek Ar | Anbotek | C Anbot | ⊠A | □В | □С |
| COM Port | potek Anbote | points | nbotek | Anbotel | C Ant | ⊠A | B | C |
| Screw | Anboren Anb | points | Anbotek | ok Anb | C | ⊠A | □В | □C |
| Slot | Anboatek 4 | points | Aupor | ooiek A | A _{nbotek} | ⊠A | B | □ C |
| Metal | k Anbotek 4 | points | yek Vu | anbotek | C Ambore | ⊠A | В | □ C |
| Button | otek Anbote | points | hotek | Anbotek | C Amb | ⊠A | B | C |
| Light | inboten And | points | Anbotek | Anbo Anbo | A | ⊠A | В | □С |
| HCP | Anbotek 4 | points | Anbore | | Canborek | ⊠A | □В | □C |
| VCP of the front | Anbotek 4 | points | lek Vur | | C Amborel | ⊠A | B | □С |
| VCP of the rear | atek Anbote | points | botek | Anborek | C Amb | ⊠A | В | □ C % |
| VCP of the left | nboten And 4 | points | Anbotek | K Aupo | C | ⊠A | В | □С |
| VCP of the right | Anbotek 4 | points | Anbore | otek An | Chotek | ⊠A | □В | □С |
| Note: N/A | k vupotek | Aupoten | ak Aug. | -botek | Anborek | Anbor | otek | N. Vupot |

Shenzhen Anbotek Compliance Laboratory Limited





Report No.: 18230EC20193501 Page 34 of 58

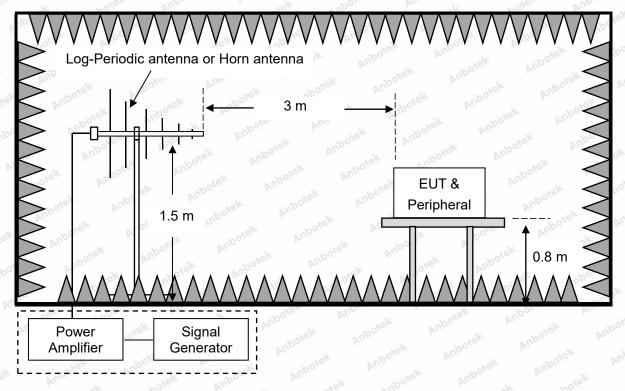
9. RF Field Strength Immunity Test

9.1. Test Specification

| Test Standard: | EN 55035 | And Stek | Vupotek Vupo, Vk Vi | | |
|------------------------|---|--------------------|-------------------------------|--|--|
| Basic standard: | IEC 61000-4-3: 2006+A1:2007+A2:2010 | | | | |
| Performance criteria: | A Amorek | A Anton Anton | A abotek Anbote A | | |
| Frequency Range: | ⊠80MHz to 1000MHz | ⊠ Spot frequencies | ☐ Additional spot frequencies | | |
| Test level: | 3 V/m | 3 V/m | 3 V/m | | |
| Modulation: | 1kHz Sine Wave, 80%, AM Modulation | | | | |
| Frequency Step: | 1 % of preceding frequency value Horizontal and Vertical | | | | |
| Polarity of Antenna: | | | | | |
| Test Distance: | 3 m | Anbo ek abotek | Anbore And Lotek | | |
| Antenna Height: | 1.5 m | Anbox ak abo | ek Anbores Anborek | | |
| Dwell Time: | at least 0.5s | Aupo, ok | hotek Anbotes Anb | | |
| Spot frequencies: 1800 | MHz, 2600 MHz, 3500 M | IHz and 5000 MHz; | Additional spot frequencies: | | |

Spot frequencies: 1800 MHz, 2600 MHz, 3500 MHz and 5000 MHz; Additional spot frequencies: 80 MHz, 120 MHz, 160 MHz, 230 MHz, 434 MHz, 460 MHz, 600 MHz, 863 MHz and 900 MHz.

9.2. Test Setup



Shenzhen Anbotek Compliance Laboratory Limited





Report No.: 18230EC20193501 Page 35 of 58

9.3. Test Procedure

The procedure defined in this part requires the generation of electromagnetic fields within which the test sample is placed and its operation observed. To generate fields that are useful for simulation of actual (field) conditions may require significant antenna drive power and the resultant high field strength levels. To comply with local regulations and to prevent biological hazards to the testing personnel, it is recommended that these tests be carried out in a shielded enclosure or semi-anechoic chamber.

- a. The antenna is placed 3 m from the equipment. The required field strength is determined by placing the field strength meter(s) on top of or directly alongside the equipment under test and monitoring the field strength meter via a remote field strength indicator outside the enclosure while adjusting the continuous-wave to the antenna.
- b. The test shall normally be performed with the generating antenna facing each side of the EUT. When equipment can be used in different orientations (i.e. vertical or horizontal) all sides shall be exposed to the field during the test. When technically justified, some EUTs can be tested by exposing fewer faces to the generating antenna. In other cases, as determined for example by the type and size of EUT or the frequencies of test, more than four azimuths may need to be exposed.
- The polarization of the field generated by each antenna necessitates testing each selected side twice,
 once with the antenna positioned vertically and again with the antenna positioned horizontally.
- d. The step size of the frequency is set to 1%. The dwell time at each frequency shall not be less than the time necessary for the EUT to be exercised and to be able to respond. However, the dwell time should not exceed 5 s at each of the frequencies during the scan.

9.4. Test Results

PASS

Please refer to the following page.







Report No.: 18230EC20193501 Page 36 of 58

RF Field Strength Susceptibility Test Results

| Test Result: | ⊠ Pas | s ☐ Fail | Temperature: | 23.9° | bote, Aupotek |
|--------------------|---------------------|------------------------|--------------------|--------------|-----------------|
| Power Supply: | AC 230 | V, 50Hz | Humidity: | 52% | |
| tek Vupo, | bu. potek | Anbores And | tek anbotek | Aupora | Projek Vi |
| Frequency Range | Antenna Polarity | R.F. Field Strength | Dwell Time | Azimuth | Result |
| Anbotek An | | lek Anboten | Anbotek | Front | oo atek Anbotek |
| 80 MHz ~ 1000 | Amborek Ambo | poten Anbo | ek uboten | Rear | ⊠ A □ B |
| MHz | | 3 V/m | otek Vupo | Left | C |
| poter And | ak Anbotek | Anbo, Potek | Anbotek Anbot | Right | Anbotek K |
| 760 | otek Anbore | ek Anbotek | Anborek An | Front | otek Aupore. |
| Spot | Anbotek Anbot | tek abotek | Anbotek Anbotek | Rear | ⊠A |
| frequencies | H/V M | 7.0 | atek Anbotek | Left | |
| potek Anbotek | Anbotek Anbotek | Anbotek Ant | otek Anbote | Right | Anbo, Potek |
| Anbotek Anbot | otek Anbotek | Anbotek | Anbotek Anb | Front | rek Antotek |
| Additional spot | H/V | 3 V/m | anbote" | Rear | □ A orek |
| frequencies | | 3 V/m | k Anbotek | Left | ☐ C |
| k Aupo, | | ru, | otek Anboten | Right | Anbotek Anb |
| Note: N/A | | Anborek A | Anbotek Anbote | otek Anbotek | Anbotek |
| | | | | | |





Report No.: 18230EC20193501 Page 37 of 58

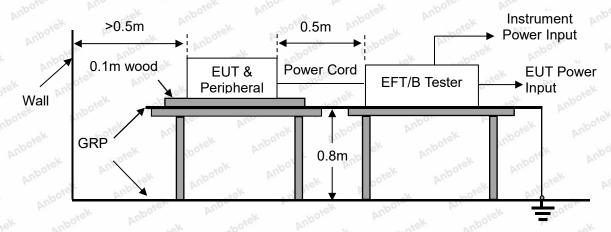
10. Electrical Fast Transient/Burst Immunity Test

10.1. Test Specification

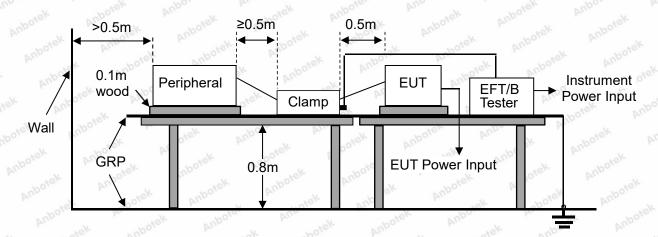
| Test Standard: | EN 55035 |
|-----------------------|--|
| Basic standard: | IEC 61000-4-4: 2012 |
| Performance criteria: | B tek abotek Anbotek Anbotek Anbotek Anbotek |
| Test Level: | □ 1 kV, AC mains power ports |
| | ☐ 0.5 kV, DC network power ports |
| | □ 0.5 kV, Analogue/digital data ports |

10.2. Test Setup

AC mains power ports and DC network power ports:



Analogue/digital data ports:









Report No.: 18230EC20193501 Page 38 of 58

10.3. Test Procedure

The table-top EUT is placed on a table that is 0.8 m height, a ground reference plane is placed on the table, and uses 0.1 m insulation between the EUT and ground reference plane. The floor-standing EUT is placed on a ground reference plane and insulated from it by an insulating support with a thickness of 0.1 m. This reference ground plane shall project beyond the EUT by at least 0.1 m on all sides and the minimum distance between EUT and all other conductive structure, except the ground plane beneath the EUT, shall be more than 0.5 m.

All cables to the EUT shall be placed on the insulation support 0.1 m above the ground reference plane. Cables not subject to electrical fast transients shall be routed as far as possible from the cable under test to minimize the coupling between the cables.

10.4. Test Results

PASS

Please refer to the following page.





Page 39 of 58 Report No.: 18230EC20193501

Electrical Fast Transient/Burst Test Results

| Test Result: | ⊠ Pass □ | Fail Temperat | ture: 23 | .2℃ |
|---------------------------------------|-------------------|----------------|-------------------|----------------|
| Power Supply: | AC 230V, 50H | z Humidity: | 49 | % Anborek Anbo |
| tek Aupo | abotek Anbote | Ann | Anbotek Anbo | ek spotek Ar |
| Ports | Polarity | Inject Time(s) | Test Voltage (kV) | Result |
| AC mains power ports | otek † potek | 120 s | 1.0 kV | ⊠A □B □C |
| DC network power ports | Anbotek ± Anbotek | 120 s | 0.5 kV | □A □B □C |
| Analogue/digital data ports (xx Line) | Anboro An | 120 s | 0.5 kV | □А □В □С |
| Note: N/A | rek Anbotes | Anbotek Anbote | otek Anbotek | Anbotek Anbote |





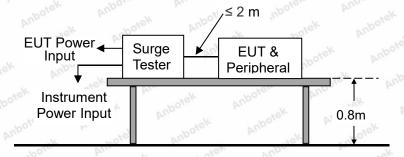
Report No.: 18230EC20193501 Page 40 of 58

11. Surge Immunity Test

11.1. Test Specification

| Test Standard: | | EN 55035 |
|-----------------|------------------------------|--|
| | Basic standard: | IEC 61000-4-5: 2014+A1:2017 |
| A.O | | ⊠ 1 kV, Line to Line, Criterion B |
| 5 | AC power port: | ☐ 2kV, Line to Earth, Criterion B |
| Test | DC network power port: | □ 0.5kV, Line to Reference ground, Criterion B |
| level | Coaxial or shielded port: | □ 0.5kV, Shield to ground, Criterion B |
| | Unshielded symmetrical port: | ☐ 1 kV and 4 kV, lines to ground , Primary protection, Criterion C |
|)) | | ☐ 1 kV, lines to ground , Non primary protection, Criterion C |
| Numl | per of surges | 5 (for each combination of parameters) |
| Repetition rate | | 1 minute / time |
| Polar | ity: | Positive / Negative |
| Phase angle: | | 90°, 270° (Only AC mains power ports) |

11.2. Test Setup



11.3. Test Procedure

Table-top EUT is placed on a table of 0.8 m heights above a metal ground reference plane. Floor standing EUT is placed on a ground reference plane and insulated from it by an insulating support with a thickness of 0.1 m. The length of the power cord between the EUT and the coupling/decoupling network is not more than 2 m, and the length of the interconnection line between the EUT and the coupling/decoupling network is not more than 2 m. The tests were done at repetition rate 1 per minute.

11.4. Test Results

PASS

Please refer to the following page.





Report No.: 18230EC20193501 Page 41 of 58

Surge Immunity Test Results

| 200 | Y wolfe | Ville | 494 | 100 | A | - V 1070 |
|--------------------------------|--------------------|-----------------------------|---------------------|-------------------|-------------|---------------------------------|
| Test Result: | ⊠ Pass | s 🗌 Fail | Temperature : | Anbotek | 23.2℃ | otek Anbotek |
| Power Supply : | AC 230\ | V, 50Hz | Humidity: | Anbore | 49% | anbotek Anbo |
| rek Anbourek | botek | Aupolo Au | otek Anbotek | AUP | -ak | bolek A |
| Location | Polarity | Phase Angle | Number of Pulse | Pulse \ (k | - O/- | Result |
| | rt (Waveform: 1. | 2 us / 50 us (8 us | s / 20us)) | | | |
| Anbotek | Anbotek Anbo | □ 0° ⊠ 90° □ 180° □ 270° | 5 | 0.5, | 1kV | ⊠A□B□C |
| ek L-Norek | Antotek | □ 0° □ 90° □ 180° ⊠ 270° | potek 5 Anbotek | 0.5, | 1kV | ⊠A□B□C |
| Anbotek Anbot | otek Yupotek | □ 0° ⊠ 90° □ 180° □ 270° | Amborett Ambor | 0.5, 1 | , 2kV | □A□B□C |
| L-GND | Pupolek - Pupol | □ 0° □ 90° □ 180° ⊠ 270° | An 5 | 0.5, 1 | , 2kV | □A □B □ C |
| k Anbotek | Anbotek An | □ 0° ⊠ 90° □ 180° □ 270° | 5 Amborek | 0.5, 1 | , 2kV | □A□B□C |
| N-GND | k Atbolek | □ 0° □ 90° □ 180° ⊠ 270° | Anborek 5 Anbore | 0.5, 1 | , 2kV | □A □B □ C |
| □ DC network p | ower ports (Wa | veform: 1.2 us / 5 | 50 us (8 us / 20us) | hotek. | Anbote | Anbo |
| Line to | inbotek + Anbo | sek / abotek | Anbois | 0.5 | kV 📶 | □A□B□C |
| Reference ground | Anbotek Ant | or I above | -5 | 0.5 | kV | □A□B□C |
| ☐ Analogue/dig | ital data ports (V | Vaveform: 10 us / | 700 us (5 us / 32 | 0us)) : <u>xx</u> | ː lines(注明》 | 则试线缆,如没有删掉 |
| 黄色部分) | k anbotek | Aupo, ok | hotek Anbote | b'u | rek | nbotek |
| Tipos to ground | tek + nbotek | Anbore | hotek5 Anb | 0.5, | 1kV | $\square A \square B \square C$ |
| Lines to ground | tek - aborel | ANDONE | 5 | 0.5, | 1kV | □A□B□C |
| ☐ Analogue/dig <u>黄色部分)</u> | ital data ports (V | Vaveform: 10 us / | 700 us (5 us / 32 | 0us)) : <u>xx</u> | ilines(注明》 | 则试线缆,如没有删掉 |
| And | Anboret A | upo tek l | tek 5.nbotts | 0.5, 1, | 2, 4kV | □A□B□C |
| Lines to ground | Arbotek | Anbo | abotek 5 Anbotes | 0.5, 1, | 2, 4kV | □A □B □C |
| ☐ Analogue/dig | ital data ports (V | Vaveform: 1.2 us | / 50 us (8 us / 20t | us)): Co | paxial or s | shielded lines |
| Anbote: Ant | hotek + Anbotek | Vupo, | 5 | 0.5 | PULL | □A□B□C |
| Shield to ground | abotek - Anbo | lek Vupo, | 5 rek | 0.5 | PULL | |
| Note: N/A | Anbotek An | bosen Aupo | tek Anbotek | Anbore | otek Ar | Anbotek Anbo |

Shenzhen Anbotek Compliance Laboratory Limited





Report No.: 18230EC20193501 Page 42 of 58

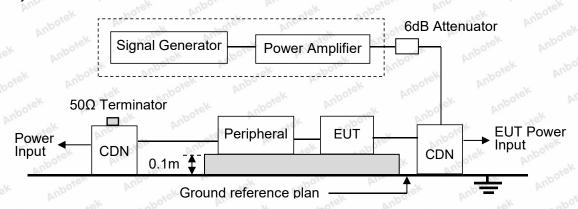
12. Injected Currents Susceptibility Test

12.1. Test Specification

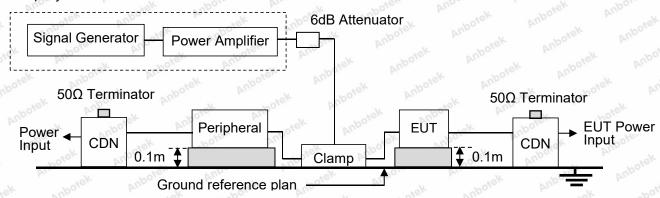
| Test Standard: | EN 55035 | rek anborek Ant | Sotek Anbotek Anbo |
|-----------------------|------------------------|-----------------|--------------------|
| Basic standard: | IEC 61000-4-6: 2013 | abotek Anbotek | Anbotek Ambotek An |
| Performance criteria: | Abotek Anbo | Anbotek Anbotek | Anbotek Anbotek |
| Frequency range: | 0.15M to 10MHz | 10M to 30MHz | 30M to 80MHz |
| Test level: | 3V Anborek Anbore | 3V to 1V | 1V Moore Annual |
| Modulation: | AM 80%, 1kHz sine-wave | Botek Anbotek A | inbotes Anti- |
| Frequency Step: | 1% of fundamental | Anbotek Anboten | Anbotek Anbotek |

12.2. Test Setup

CDN injection:



Clamp injection:



Shenzhen Anbotek Compliance Laboratory Limited





Report No.: 18230EC20193501 Page 43 of 58

12.3. Test Procedure

- a. The EUT and peripheral are placed on an insulating support of 0.1 m height above a ground reference plan. The distance between EUT and CDN is 0.1 m to 0.3 m. All cables exiting the EUT are supported at a height of at least 30 mm above the ground reference plan.
- b. The frequency range is swept from 150 kHz to 80MHz, with the signal 80% amplitude modulated with a 1 kHz sine wave. The rate of sweep did not exceed 1.5x 10-3 decade/s. The frequency range is swept incrementally. The step size was 1% of fundamental from 0.15MHz to 80MHz.
- c. The dwell time at each frequency isn't less than the time necessary for the EUT to be able to respond.

12.4. Test Results

PASS

Please refer to the following page.







Report No.: 18230EC20193501 Page 44 of 58

Injected Currents Susceptibility Test Results

| Test Result: | ⊠ Pass ☐ Fail | Temperature: | 23℃ |
|--------------------------|----------------------|------------------------|-----------------|
| Power Supply: | AC 230V, 50Hz | Humidity: | 48% |
| olek Aupon K | otek Anbotes Anb | tek abotek Al | ipos k kotek Ar |
| Frequency Range (MHz) | Injected Position | Strength (Un-modulated | Result |
| 0.15 ~ 10 | AC Mains | 3V | ⊠A □B □C |
| 10 ~ 30 | AC Mains | 3V to 1V | ⊠A □B □C |
| 30 ~ 80 | AC Mains | notek ATV AT | ⊠A □B □C |
| poter Anbe | Inpotek Anboundek An | Anbotek Anboter | Anbotek Anbotek |
| 0.15 ~ 10 | Anbotek Anbotek | 3V | □A □B □C |
| 10 ~ 30 | Anbotek Anbotek | 3V to 1V | □A □B □C |
| 30 ~ 80 | tek Anbotek Anbot | 1V | □A □B □C |
| Note: N/A | nbotek Anbotek An | Anbotek Anbotek | Anbotek Anbotek |





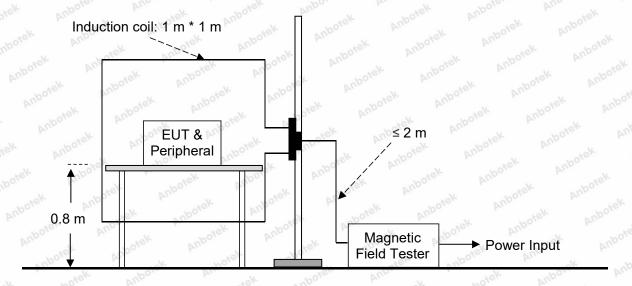
Report No.: 18230EC20193501 Page 45 of 58

13. Power Frequency Magnetic Field Immunity Test

13.1. Test Specification

| Y. | Test Standard: | EN 55035 | 3 |
|-----|----------------------|--|---|
| 0 | Basic Standard | IEC 61000-4-8: 2009 | d |
| 7/2 | Performance criteria | Apotek Anbotek Anbotek Anbotek Anbotek Anbotek | |
| | Test level | 1A/m | 6 |

13.2. Test Setup



13.3. Test Procedure

Table-top EUT is placed on a table that is 0.8 m height. Floor standing EUT is placed on a ground reference plane and insulated from it by an insulating support with a thickness of 0.1 m.

The EUT is placed in the middle of an induction coil. The proximity method is used when the EUT does not fit into the standard inductive coil

13.4. Test Results

Not applicable







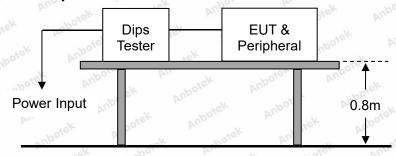
Report No.: 18230EC20193501 Page 46 of 58

14. Voltage Dips and Interruptions Immunity Test

14.1. Test Specification

| Test Standard: | EN 55035 |
|-----------------|--|
| Basic standard: | IEC 61000-4-11: 2020 |
| Test level: | ⊠ 0%, 0.5 period, Criterion B |
| | ⊠ 70%, 25 periods for 50Hz, Criteria C |
| | ⊠ 0%, 250 periods for 50Hz, Criteria C |
| 6 | ☐ 70%, 30 periods for 60Hz, Criteria C |
| 24 | □ 0%, 300 periods for 60Hz, Criteria C |

14.2. Test Setup



14.3. Test Procedure

- a. Where the equipment has a rated voltage the following shall apply:
- If the voltage range does not exceed 20% of the lower voltage specified for the rated voltage range, a single voltage within that range may be specified as a basis for test level specification.
- In all other cases, the test procedure shall be applied for both the lowest and highest voltages declared in the voltage range.
- b. Test Conditions
- Select operated voltage and frequency of EUT Test of interval: 10 sec.
- Level and duration: Sequence of 3 dips/interrupts.
- Voltage rise (and fall) time: 1.5 μs.
- c. Changes to occur at 0 degree crossover point of the voltage waveform.

14.4. Test Results

PASS

Please refer to the following page.





Page 47 of 58 Report No.: 18230EC20193501

Voltage Dips and Interruptions Test Results

| Test Result: | ⊠ Pass □ Fail | Temperature : | 23.2℃ |
|--------------------|---|-----------------------|-------------------|
| Power Supply : | AC 230V, 50Hz | Humidity: | 49% |
| tek Augo ok k | otek Anbore Am | otek Anbotek Ant | ok hotek Ar |
| Test Level % UT | Voltage Dips & Short Interruptions % UT | Duration (in periods) | Result Anbotek |
| Anbotek O Anbotek | 100 | Anbore 0.5P | □A ⊠B □C |
| ek Anbore | 30 | 25P | □A □B ⊠C |
| potek Anbotek Anb | abotek Anbotek An | boto Ambotek | hbotek Anbotek |
| Anbotek Anbotek | Anbotek Anbotek | Ambotek Anbotek | Anbotek Anbotek |
| Anbo. A Morek | Anbore, And | anbotek Anbo. | hotek Anbote |
| Test Level % UT | Voltage Dips & Short Interruptions % UT | Duration (in periods) | Result |
| botek Opotek A | 100 | 250P | □A □B ⊠C |
| Anbotek Anbotek | Anbotek Anbotek | Anbore Anborek | Anbotek Anbotek |
| Anbotek Anbotek | Anbotek Anbote | k Anbotek Anbotek | ek abotek Anbote |
| Note: N/A | tek Anbotek Anb | obotek Anbotek Anbo | botek Anbotek Anb |
| v woter Ar | | | |





Report No.: 18230EC20193501 Page 48 of 58

APPENDIX I -- TEST SETUP PHOTOGRAPH

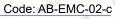
Photo of Power Line Conducted Emission Test



Photo of Asymmetric Mode Conducted Emission at Telecom Port



Shenzhen Anbotek Compliance Laboratory Limited









Report No.: 18230EC20193501 Page 49 of 58

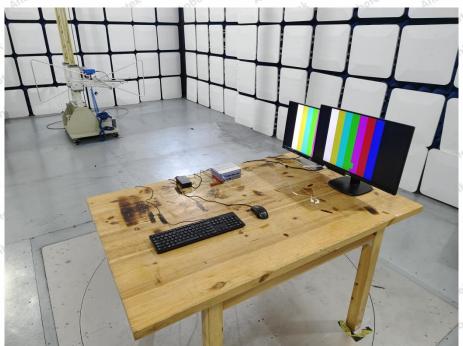
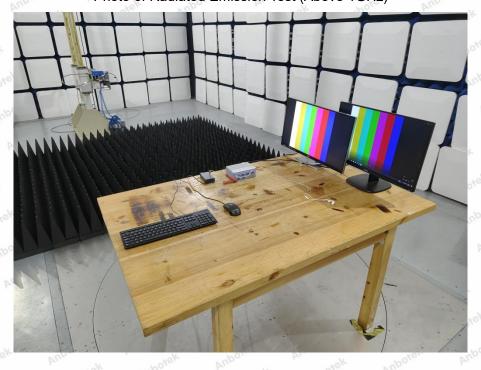
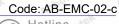


Photo of Radiated Emission Test (Below 1 GHz)





Shenzhen Anbotek Compliance Laboratory Limited







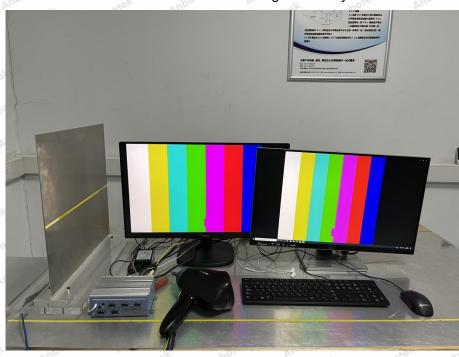


Report No.: 18230EC20193501 Page 50 of 58

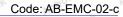


Photo of Harmonic Current And Flicker Test

Photo of Electrostatic Discharge Immunity Test



Shenzhen Anbotek Compliance Laboratory Limited









Report No.: 18230EC20193501 Page 51 of 58

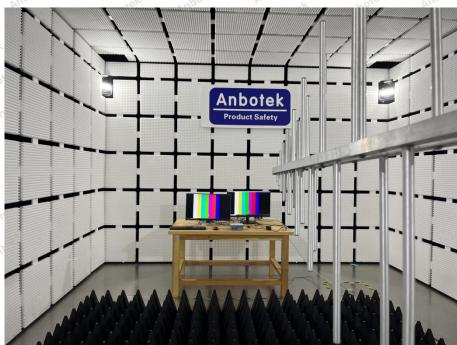


Photo of RF Field Strength Immunity Test





Shenzhen Anbotek Compliance Laboratory Limited





Report No.: 18230EC20193501 Page 52 of 58

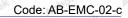




Photo of Injected Currents Susceptibility Test



Shenzhen Anbotek Compliance Laboratory Limited



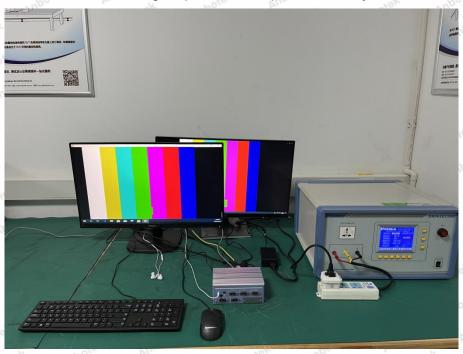






Report No.: 18230EC20193501 Page 53 of 58

Photo of Voltage Dips and Interruptions Immunity Test







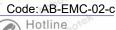
Report No.: 18230EC20193501 Page 54 of 58

APPENDIX II -- EXTERNAL PHOTOGRAPH





Shenzhen Anbotek Compliance Laboratory Limited

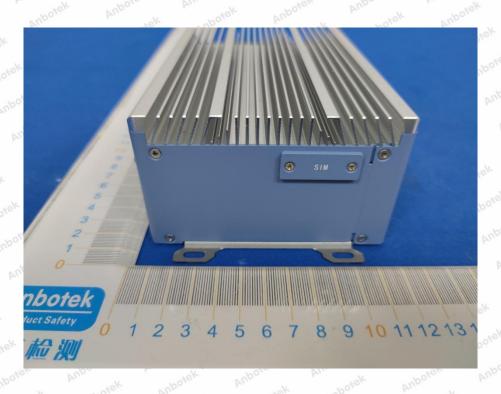






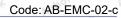


Report No.: 18230EC20193501 Page 55 of 58





Shenzhen Anbotek Compliance Laboratory Limited









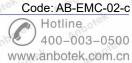
Report No.: 18230EC20193501 Page 56 of 58





Shenzhen Anbotek Compliance Laboratory Limited

lek .







Report No.: 18230EC20193501 Page 57 of 58

APPENDIX III -- INTERNAL PHOTOGRAPH









Report No.: 18230EC20193501 Page 58 of 58

CE Label

- The CE conformity marking must consist of the initials 'CE' taking the following form:
 If the CE marking is reduced or enlarged, the proportions given in the above graduated drawing must be respected.
- 2. The CE marking must have a height of at least 5 mm except where this is not possible on account of the nature of the apparatus.
- 3. The CE marking must be affixed to the product or to its data plate. Additionally it must be affixed to the packaging, if any, and to the accompanying documents.
- 4. The CE marking must be affixed visibly, legibly and indelibly.

 It must have the same height as the initials 'CE'.

| dr. Athorek | End o | f Report | notek shore |
|-------------|-------|----------|-------------|
| | | Coport | |

